

Notice of References Cited	Application/Control No. 10/750,552		Applicant(s)/Patent Under Reexamination DING ET AL.	
	Examiner J. Derek Rutten		Art Unit 2192	Page 1 of 1

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*	B	US-6,421,668 B1	07-2002	Yakhini et al.	707/6
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.